

http://www.flomlabs.com info@flomlabs.com

Date: March 03, 2009

Applicant: Novatel Wireless Inc.

9645 Scranton Rd, Suite 205

San Diego, CA 92121

Attention of: John Spall, Project Manager

Ph: 858-812-0697, Fax: 858-450-7183

email: jspall@nvtl.com

Equipment: PKRNVWE725 Collocated with QDS-BRCM1031 802.11

FCC ID: PKRNVWE725

FCC Rules: Radio Frequency Radiation Exposure Limits

47 CFR 1.1310

MPE - Mobiles Fixed Based Station

Gentlemen:

Enclosed please find your copy of the Supplemental Test Data Report, the whole for Environmental Assessment (MPE) of the referenced equipment as shown.

Please allow from 8-12 weeks to hear from the Commission, who may request additional data or information, and even a sample for pre-grant audit testing.

Should you need any clarification, just fax or phone. Thank you again for this order - it has been a pleasure to be of service.

Sincerely yours,

Hoosamuddin S. Bandukwala, Lab Director

enclosure(s) HSB/jhe



March 03, 2009 Date:

Federal Communications Commission Via: Electronic Filing

Attention: Authorization & Evaluation Division

Applicant: Novatel Wireless Inc.

Equipment: PKRNVWE725 Collocated with QDS-BRCM1031 802.11

FCC ID: PKRNVWE725

FCC Rules: Radio Frequency Radiation Exposure Limits

47 CFR 1.1310

MPE - Mobiles Fixed Based Station

Gentlemen:

On behalf of the Applicant, enclosed please find the Supplemental Test Data Report, the whole for Environmental Assessment (MPE) of the referenced equipment as shown.

We trust the same is in order. Should you need any further information, kindly contact the writer who is authorized to act as agent.

Sincerely yours,

Hoosamuddin S. Bandukwala, Lab Director

enclosure(s) cc: Applicant HSB/jhe



Environmental Assessment

for

Mobiles

for

FCC ID: PKRNVWE725

Model: E725

to

Federal Communications Commission

47 CFR 1.1310 (MPE)

Radio Frequency Radiation Exposure Limits

Date Of Report: March 03, 2009

On the Behalf of the Applicant: Novatel Wireless Inc.

At the Request of: Novatel Wireless Inc.

9645 Scranton Rd, Suite 205

San Diego, CA 92121

Attention of: John Spall, Project Manager

Ph: 858-812-0697, Fax: 858-450-7183

email: jspall@nvtl.com

Supervised By:

Hoosamuddin S. Bandukwala, Lab Director



Table of Contents

Rule	Description	Page	
	Test Report	3	
	Identification of the Equipment Under Test	2	
	Standard Test Conditions and Engineering Practices	3	
1.1310	Environmental Assessment	4	



Required information per ISO 17025-2005, paragraph 5.0:

a) Test Report (Supplemental)

b) Laboratory: Flom Test Labs

(FCC: 31040/SIT) 3356 N. San Marcos Place, Suite 107

(Canada: IC 2044) Chandler, AZ 85225

c) Report Number: d0930002

d) Client: Novatel Wireless Inc.

9645 Scranton Rd, Suite 205

San Diego, CA 92121

e) Identification: PKRNVWE725

FCC ID: PKRNVWE725

Description: Dell laptop model Latitude E6400 XFR-"Roush XFR"

f) EUT Condition: Not required unless specified in individual tests.

g) Report Date: March 03, 2009

h, j, k): As indicated in individual tests.

i) Sampling method: No sampling procedure used.

I) Uncertainty: In accordance with FTL internal quality manual.

m) Supervised by:

Hoosamuddin S. Bandukwala, Lab Director

n) Results: The results presented in this report relate only to the item tested.

o) Reproduction: This report must not be reproduced, except in full, without written permission

from this laboratory.



Identification of the Equipment Under Test (EUT)

Name and Address of Applicant:	Novatel Wireless Inc. 9645 Scranton Rd, Suite 205 San Diego, CA 92121				
Manufacturer:	Novatel Wireless Inc. 9645 Scranton Rd, Suite 205 San Diego, CA 92121				
FCC ID:	PKRNVWE725				
Model Number:	PKRNVWE725				
Description:	Dell laptop model Latitude E6400 XFR-"Roush XFR"				
Type of Emission:	CDMA collocated with 802.11				
Frequency Range, MHz:	CDMA 824 - 848 and 1851 - 1908 802.11 - 2412 – 2472, 5745 – 5825, and 5180 - 5700				
Power Rating, Watts: Switchable	0.296 VariableX N/A				
Modulation:	AMPS TDMA X CDMA X OTHER				
Antenna:	Helical Monopole Whip X Other				

Note: For RF Safety test antenna gain taken at the upper range of expected gain (i.e. 0 dBd) and RF Power set to highest nominal power across all channels.



Standard Test Conditions and Engineering Practices

Except as noted herein, the following conditions and procedures were observed during the testing:

In accordance with ANSI C63.4-2003 and unless otherwise indicated in the specific measurement results, the ambient temperature of the actual EUT was maintained within the range of 10° to 40°C (50° to 104 °F) unless the particular equipment requirements specify testing over a different temperature range. Also, unless otherwise indicated, the humidity levels were in the range of 10% to 90% relative humidity.

Prior to testing, the EUT was tuned up in accordance with the manufacturer's alignment procedures. All external gain controls were maintained at the position of maximum and/or optimum gain throughout the testing.

Measurement results, unless otherwise noted, are worst-case measurements.

A2LA

"A2LA has accredited Flom Test Labs, Inc. Chandler, AZ for technical competence in the field of Electrical testing. The accreditation covers the specific tests and types of tests listed on the agreed scope of accreditation. This laboratory meets the requirements of ISO 17025:2005 'General Requirements for the Competence of Testing and Calibration Laboratories' and any additional program requirements in the identified field of testing."

Please refer to www.a2la.org for current scope of accreditation.

Certificate number: 2152.01





Name of Test: Environmental Assessment

Specification: FCC: 47 CFR 1.1310

Measurement Guide: ANSI/IEEE C95.1 1992

Name of Test: R.F. Radiation Exposure

FCC Rules: 1.1307, 1.1310, 1.1311, 2.1091
Description, EUT: See page 2 of Test Report

Limits: Uncontrolled Exposure

47 CFR 1.1310 Table 1, (B) $\begin{array}{lll} 0.3\text{-}1.234 \text{ MHz:} & \text{Limit } [\text{mW/cm}^2] = 100 \\ 1.34\text{-}30 \text{ MHz:} & \text{Limit } [\text{mW/cm}^2] = (180/\text{f}^2) \\ 30\text{-}300 \text{ MHz:} & \text{Limit } [\text{mW/cm}^2] = 0.2 \\ 300\text{-}1500 \text{ MHz} & \text{Limit } [\text{mW/cm}^2] = \text{f}/1500 \\ 1500\text{-}100,000 \text{ MHz:} & \text{Limit } [\text{mW/cm}^2] = 1.0 \\ \end{array}$

Test Frequencies, MHz 824 – 848 Power, Conducted, mW = 291 Antenna Gain = 3 dBi

Antenna Model Planer Inverted F Antenna

Distance cm 20

Limit Calculations $Limit_{[mW/cm2]} = 0.549$

Test Frequencies, MHz 1851 - 1908 Power, Conducted, mW = 296 Antenna Gain = 3 dBi

Antenna Model Planer Inverted F Antenna

Distance cm 20

Limit Calculations $Limit_{[mW/cm2]} = 1.0$



PKRNVWE725 CDMA

CDMA Frequency MHz	TX Power (m)W	Power Density (mW/cm ²)	Limit (mW/cm ²)	Result
824 – 848	291	0.116	0.549	Pass
1851 - 1908	296	0.118	1.0	Pass

QDS-BRCM1031 802.11

802.11 Frequency MHz	TX Power (mW)	Power Density (mW/cm²)	Limit (mW/cm ²)	Result
2412 - 2472	159	0.172	1.0	Pass
5745 - 5825	98	0.093	1.0	Pass
5180 - 5700	107	0.043	1.0	Pass

PKRNVWE725 CDMA Collocated with QDS-BRCM1031 802.11

CDMA Frequency	802.11.a,b,g	CDMA	802.11.a,b,g	Total	Limit	Result
MHz	Frequency	Power	Power	Power	(mW/cm ²)	
	MHz	Density	Density	Density		
		(mW/cm ²)	(mW/cm ²)	(mW/cm ²)		
824 – 848	2412 – 2472	0.116	0.172	0.288	0.549	Pass
824 – 848	5745 - 5825	0.116	0.093	0.209	0.549	Pass
824 – 848	5180 - 5700	0.116	0.043	0.159	0.549	Pass
1851 - 1908	2412 – 2472	0.118	0.172	0.29	1.0	Pass
1851 - 1908	5745 - 5825	0.118	0.093	0.211	1.0	Pass
1851 - 1908	5180 - 5700	0.118	0.043	0.161	1.0	Pass

Supervised By:

Hoosamuddin S. Bandukwala, Lab Director



Testimonial and Statement of Certification

This is to certify that:

- 1. **That** the application was prepared either by, or under the direct supervision of, the undersigned.
- 2. **That** the technical data supplied with the application was taken under my direction and supervision.
- 3. That the data was obtained on representative units, randomly selected.
- 4. **That**, to the best of my knowledge and belief, the facts set forth in the application and accompanying technical data are true and correct.

Certifying Engineer:

Hoosamuddin S. Bandukwala, Lab Director